


<b>Search Notes</b>  	<b>Application/Control No.</b>  10523309	<b>Applicant(s)/Patent Under Reexamination</b>  HENNE ET AL.
	<b>Examiner</b>  Kaplan, Hal I	<b>Art Unit</b>  2836

SEARCHED			
Class	Subclass	Date	Examiner
307	100	1/22/2008	HK

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	8/15/2008	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	8/26/2008	HK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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